

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251241US2	SERIAL NO. 10/812,887		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Katsufumi EHATA			
				FILING DATE March 31, 2004	GROUP 2855		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
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AO							
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AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>JM</i>	AW	B. A. GALWAS, et al., IEEE Transactions on Instrumentation and Measurement, vol. 46, no. 2, XP-000725675, pages 511-514, "DIELECTRIC MEASUREMENTS USING A COAXIAL RESONATOR OPENED TO A WAVEGUIDE BELOW CUT-OFF", April 1, 1997					
<i>JM</i>	AX	S. O. NELSON, et al., IEEE Transactions on Instrumentation and Measurement, vol. 47, no. 5, XP-000862430, pages 1201-1204, "SENSING PULVERIZED MATERIAL MIXTURE PROPORTIONS BY RESONANT CAVITY MEASUREMENTS", October 1998					
	AY						
	AZ	<i>None JM</i>					
<input type="checkbox"/> Additional References sheet(s) attached							
Examiner <i>Jeff Hatahata</i>			Date Considered <i>8/19/05</i>				

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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SHEET 1 OF 1

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FOREIGN PATENT DOCUMENTS							
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	AO	6-138076	05/20/1994	JAPAN	YES	NO	X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
JM	AW	Y. IIJIMA, pages 20-23, "ELECTRONIC MONTHLY", 1998					
JM	AX	JIS R 1627, Japanese Standards Association, pages 1-18, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMICS AT MICROWAVE FREQUENCY", July 1996					
JM	AY	JIS R 1641, Japanese Standards Association, pages 1-29, "TESTING METHOD FOR DIELECTRIC PROPERTIES OF FINE CERAMIC PLATES AT MICROWAVE FREQUENCY", January 2002					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Jeff Natale</i>				Date Considered <i>8/19/05</i>			
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